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(54) **SCAN TEST METHOD FOR PROVIDING
REAL TIME IDENTIFICATION OF FAILING
TEST PATTERNS AND TEST BIST
CONTROLLER FOR USE THEREWITH**

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(57) **ABSTRACT**

A method of scan testing an integrated circuit to provide real time identification of a block of test patterns having at least one failing test pattern comprises performing a number of test operations and storing a test response signature corresponding to each block of test patterns into a signature register; replacing the test response signature in the signature register with a test block expected signature; identifying the block as a failing test block when the test response signature is different from the test block expected signature; and repeating preceding steps until the test is complete.

